

Analytical TEM

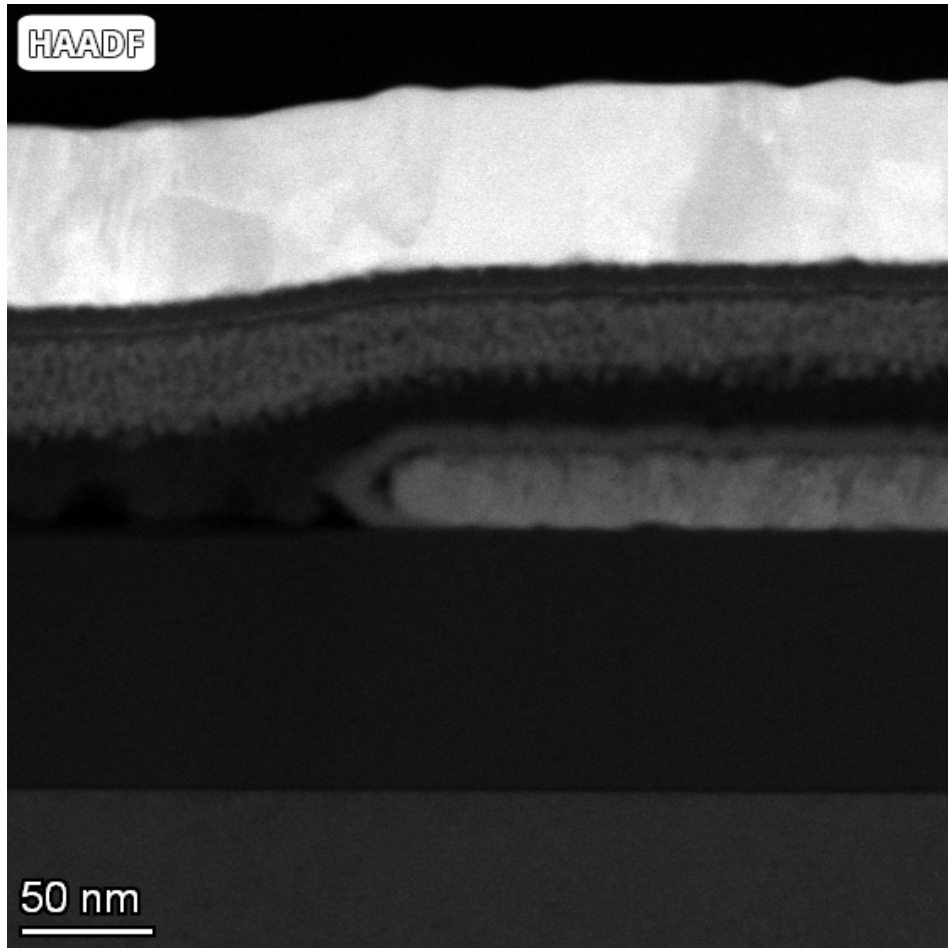
part I

Duncan Alexander

EPFL-IPHYS-LSME

EPFL Adding colour to microscopy!

- Multilayer from first STEM lecture

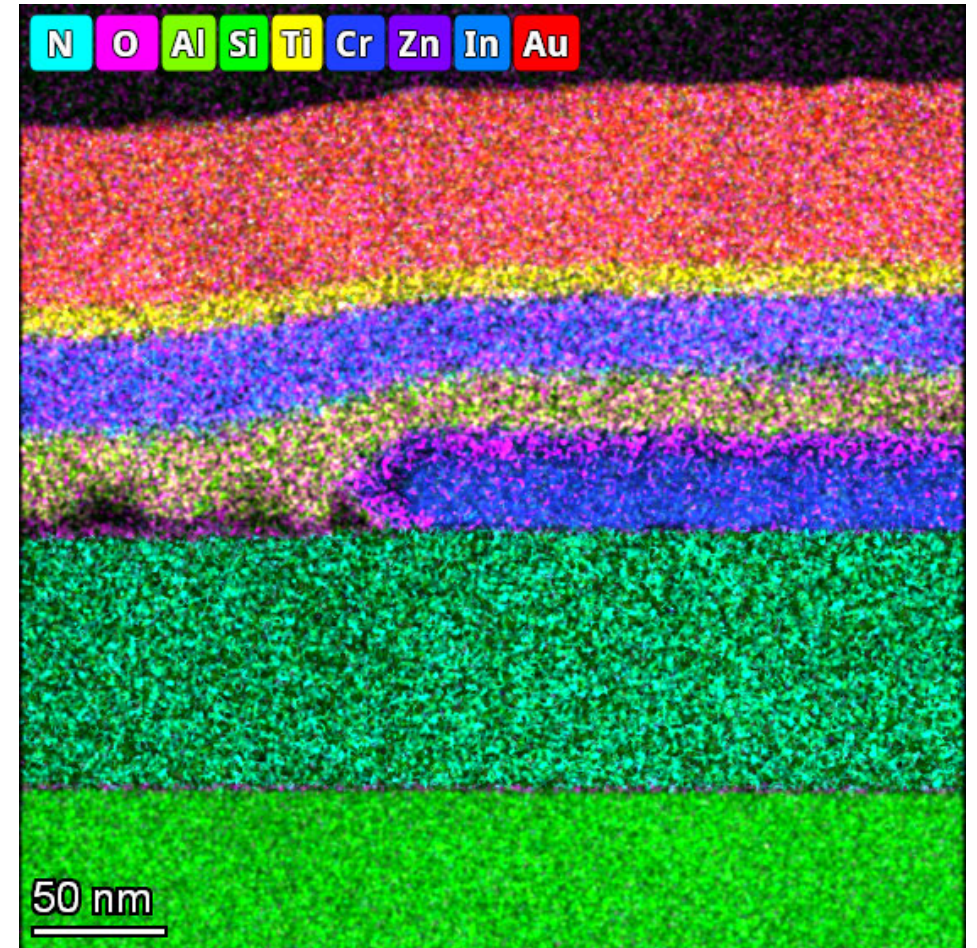
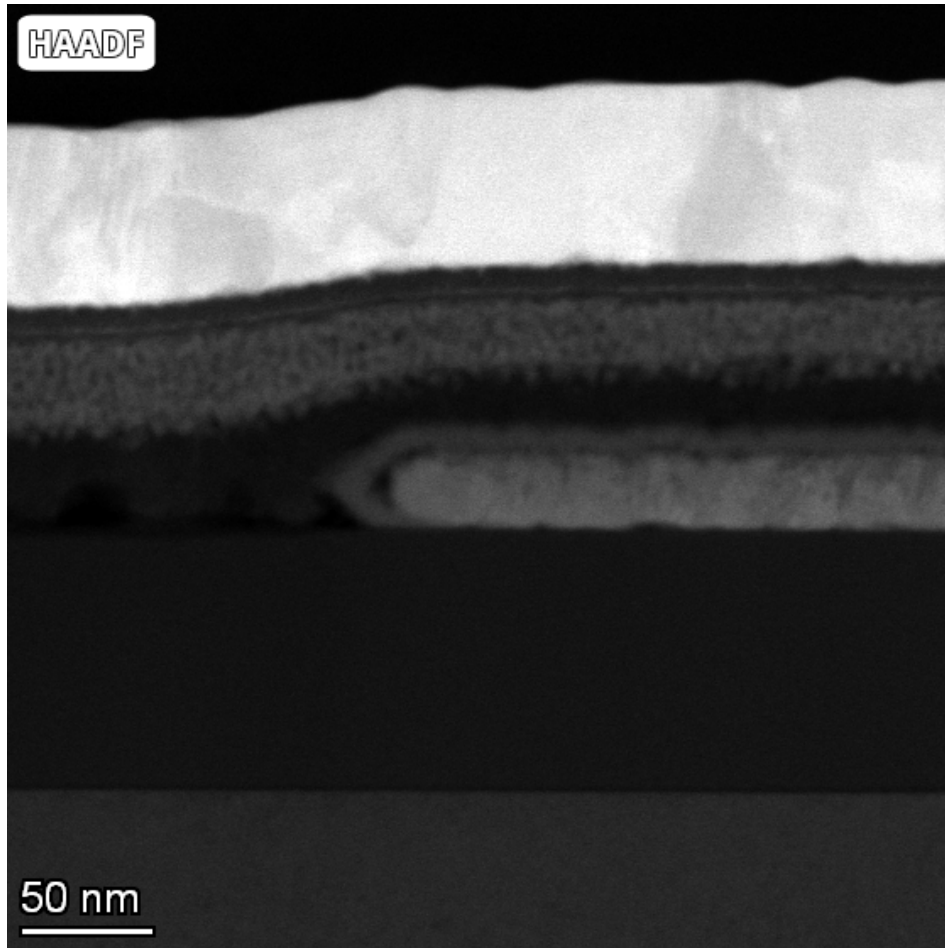


$$I \propto Z^{1.6-1.9}$$

Adding colour to microscopy!

- Multilayer from first STEM lecture

EDX spectroscopy



EPFL Contents

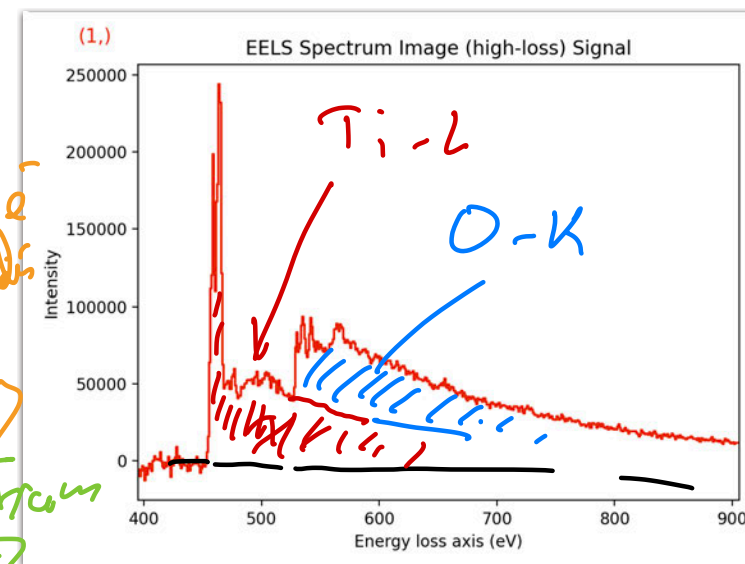
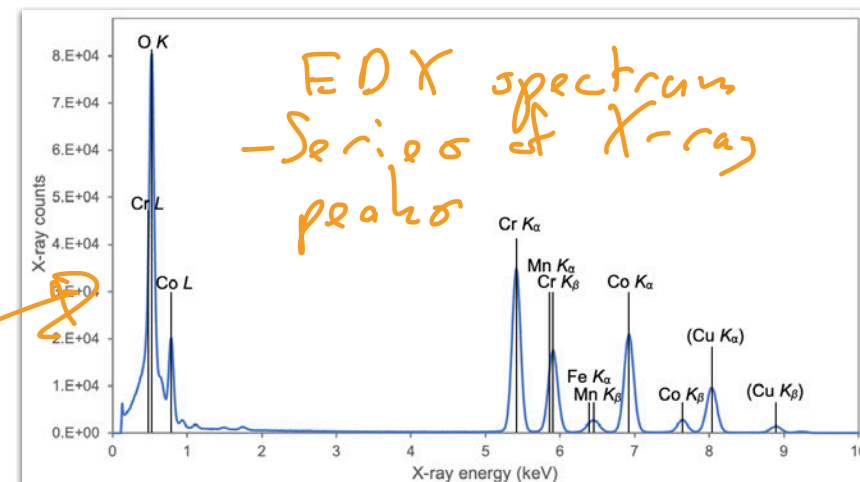
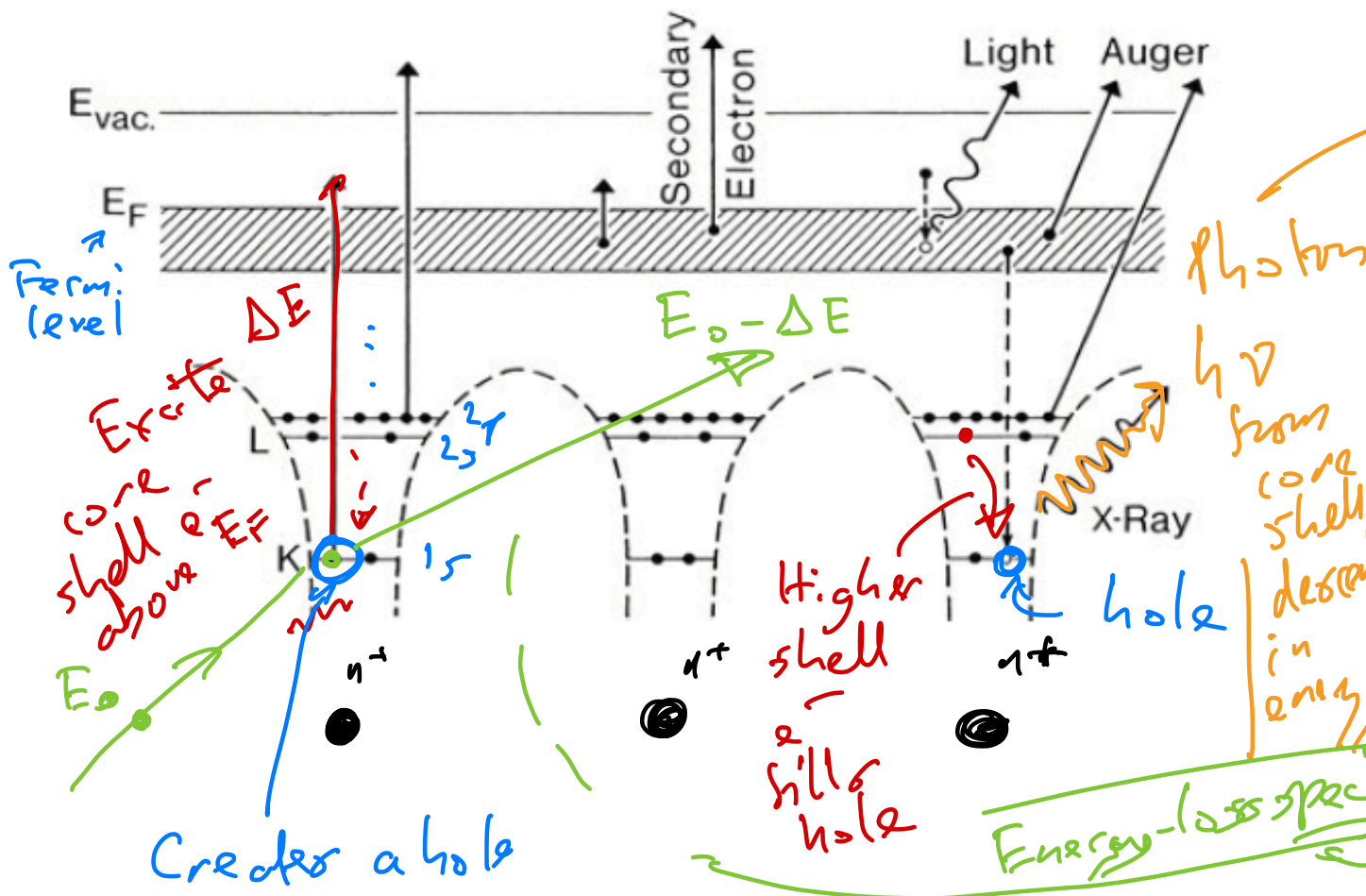
- Introduction to EDX spectroscopy and EELS
- Energy dispersive X-ray (EDX) spectroscopy
 - X-ray generation
 - EDX spectrum
 - Detector setup
 - Applications

A way to probe chemistry

[IONIZE ATOM]

Incident e^- energy E_0 E_0 : 80-300 keV (from high tension)

INNER-SHELL OUTER-SHELL DE-EXCITATION

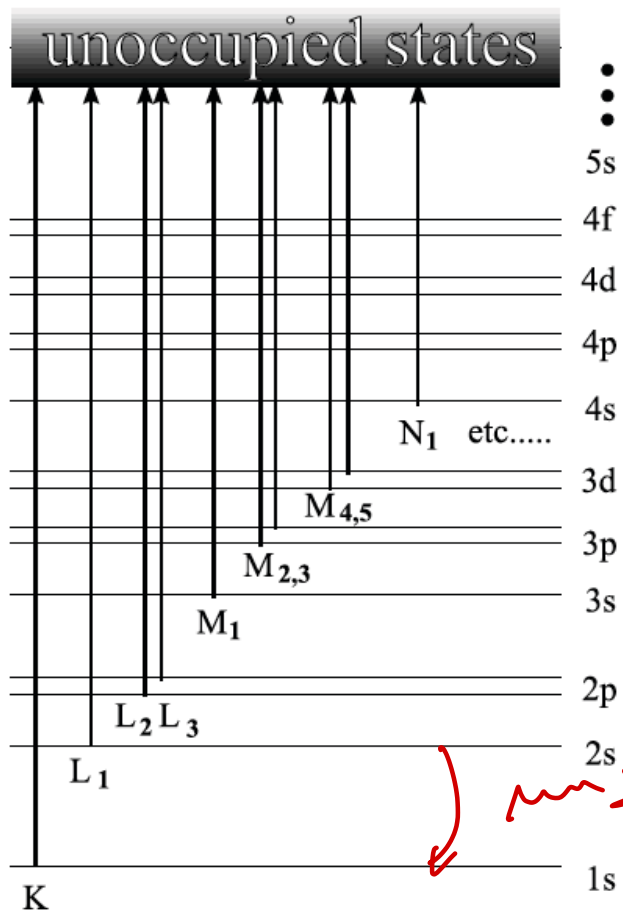


Edges and peaks nomenclature

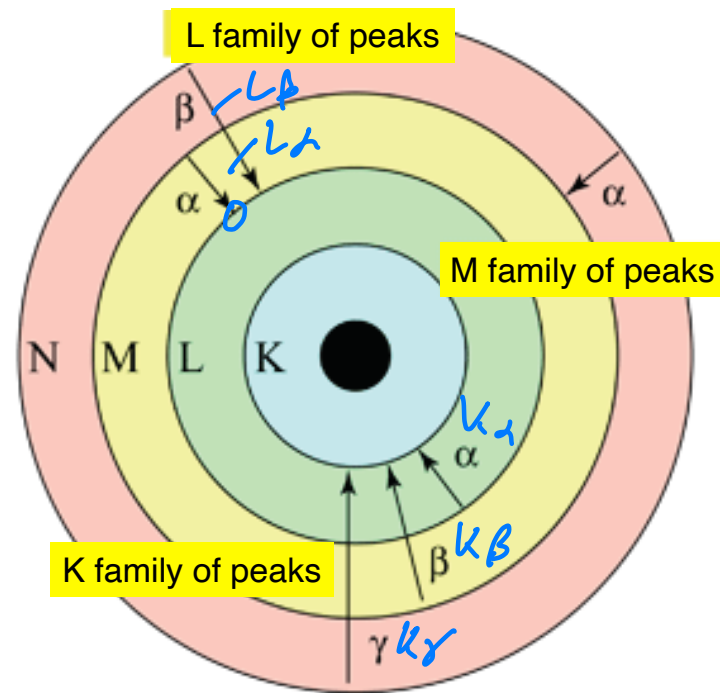
EELS

EDXS - X-ray transition

ΔE



$\rightarrow h\nu$ X-ray



$K\alpha, K\beta$
 $L\alpha, L\beta$
 $M \dots$

- EDXS: energy dispersive X-ray spectroscopy
⇒ intensity spectrum of X-ray peaks separated by energy
- EELS: electron energy-loss spectroscopy
⇒ intensity spectrum of energy lost by transmitting e^- (ΔE)
- We look at a sample containing Oxygen. We detect the Oxygen K-edge both in EELS and in EDXS. We find the transition at E_{EELS} in EELS and E_{EDXS} in EDXS
- Do we have:
 - 1) $E_{\text{EELS}} > E_{\text{EDXS}}$
 - 2) $E_{\text{EELS}} = E_{\text{EDXS}}$
 - 3) $E_{\text{EELS}} < E_{\text{EDXS}}$

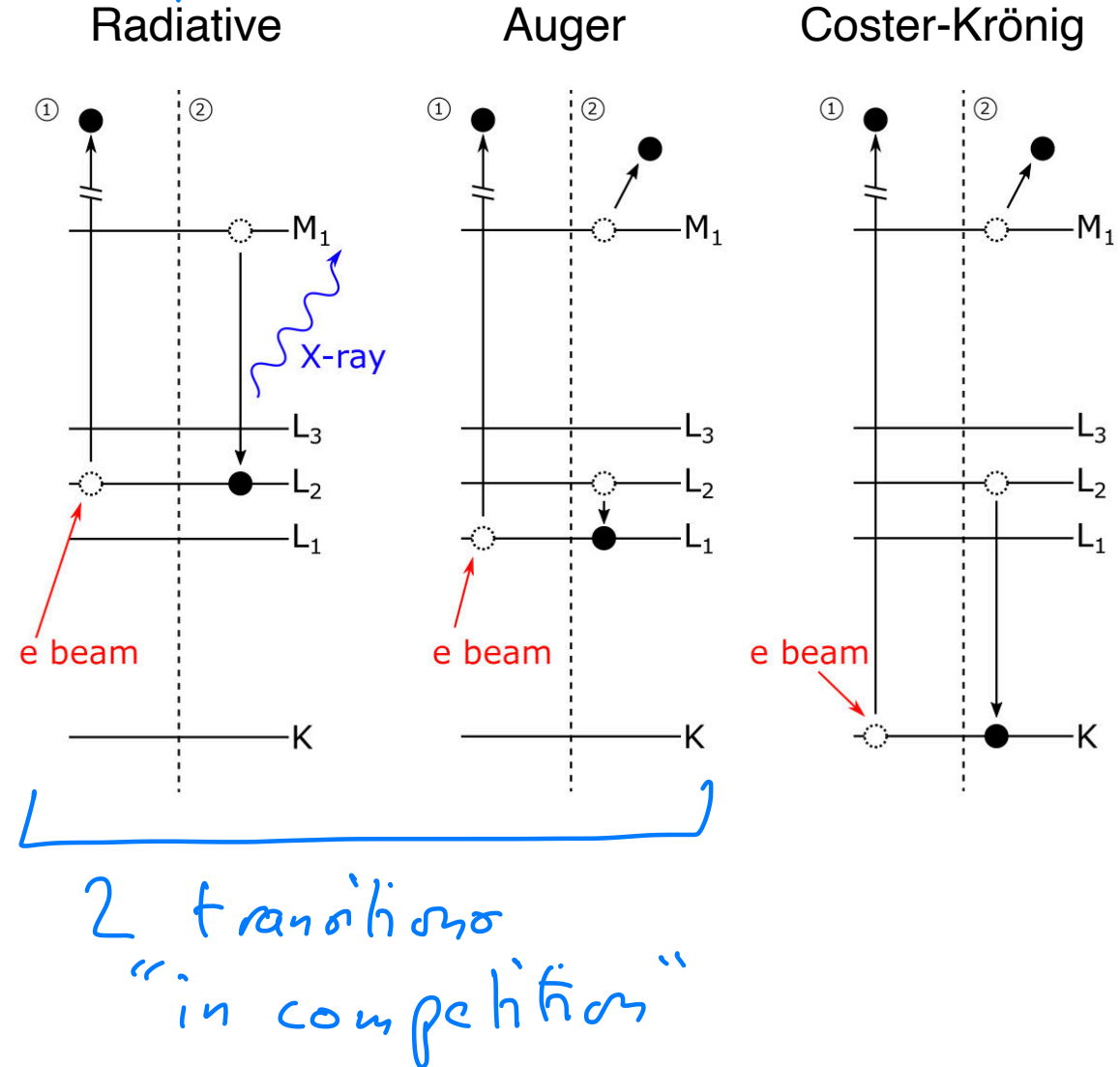
EPFL Contents

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EPFL X-ray generation

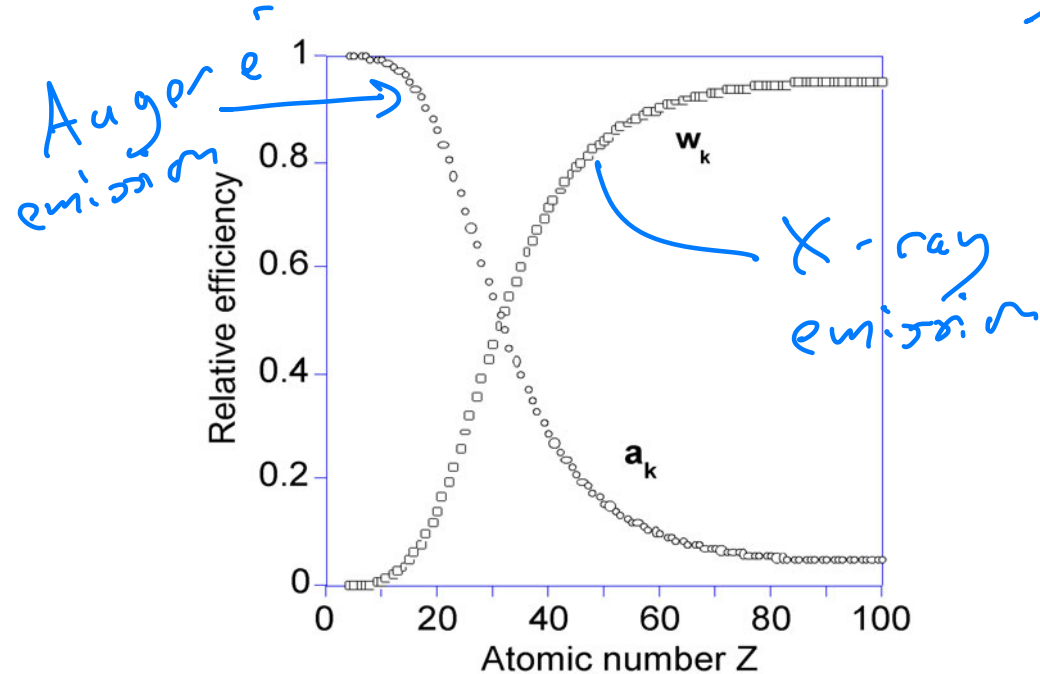
X-ray
generation

- 3 basic de-excitation process:
 - Radiative X-ray emission
 - Auger transitions/emission
 - Coster-Krönig transitions
- Complex “cascade” effects possible



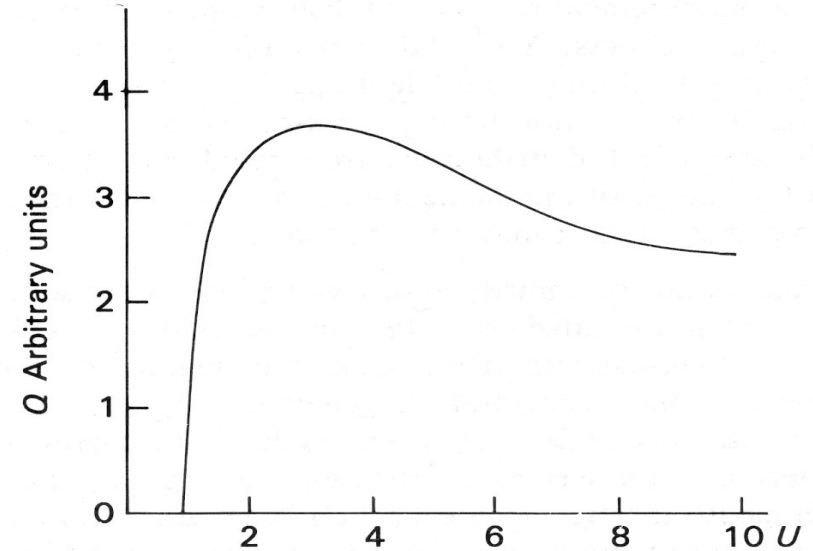
EPFL X-ray generation

Relative efficiency of X-ray and Auger emission vs. atomic number for K lines



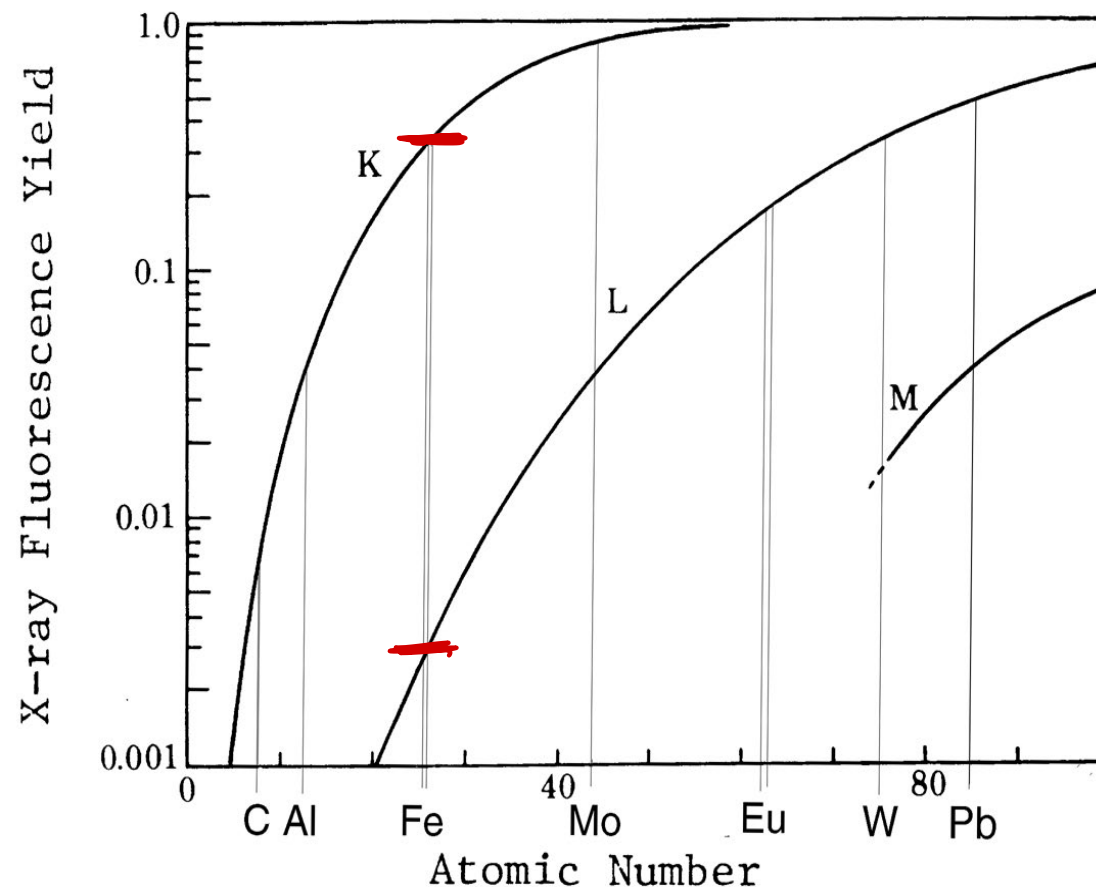
Light element atoms return to fundamental state mainly by Auger emission. For that reason, their K-lines are weak. In addition their low energy makes them easily absorbed.

Handwritten blue text: X-ray generation ↑ as Z ↑



To ionise an atom, the incident electron MUST have an energy larger than the core shell level $U > 1$. To be efficient, it should have about twice the edge energy $U > 2$.

Handwritten blue text: (S)TEM: $U \geq 60 \text{ keV}$
 \Rightarrow All X-rays excited



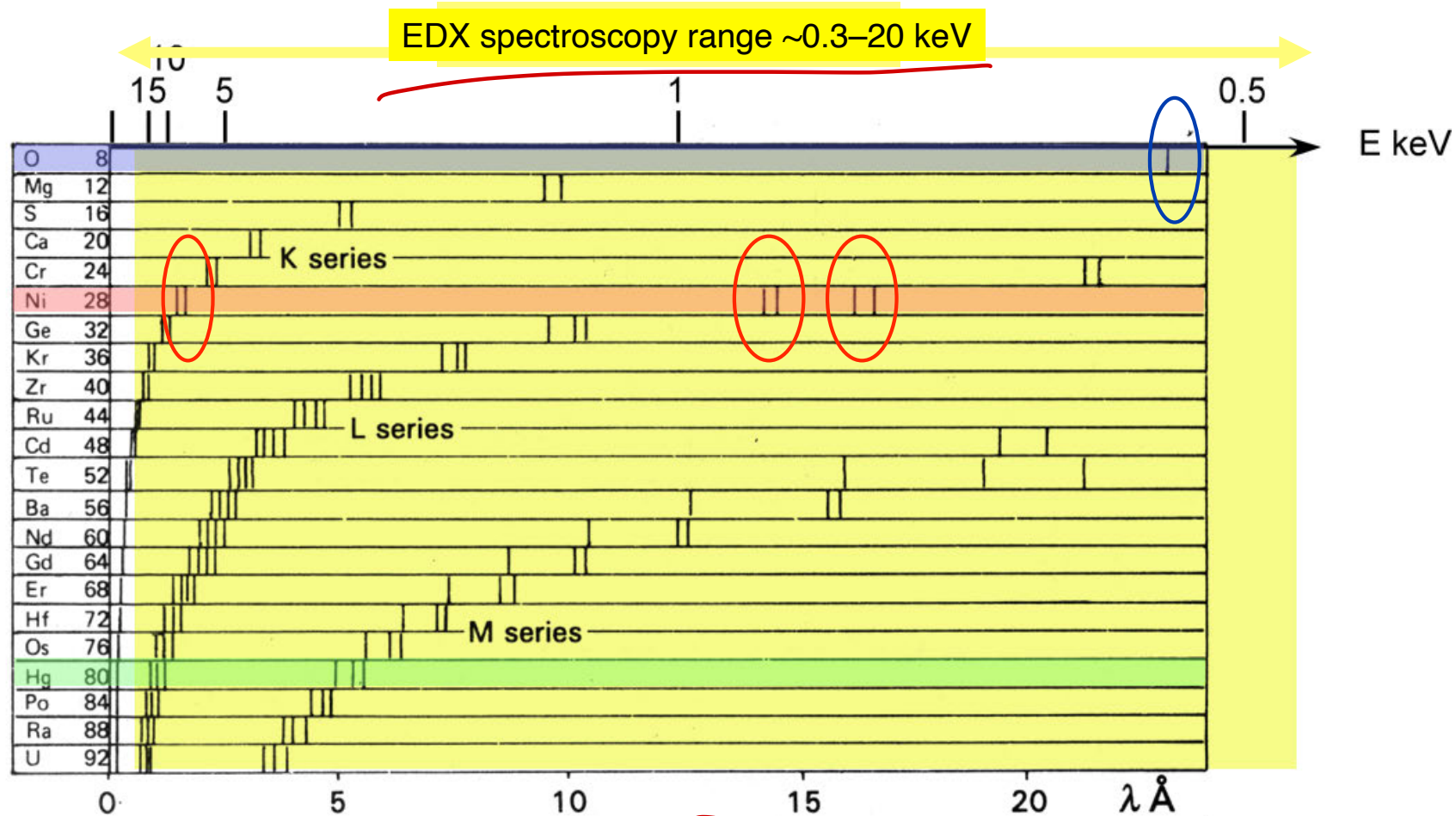
X-ray fluorescence yield for K-, L-, and M-shells, as a function of atomic number.

Probability of
ionization
+ prob. of de-excitation
as X-ray emission

↓
Peak intensity

For each Z:
"Fixed" intensity ratio
between their peaks
eg. $K_{\alpha} : K_{\beta}$
 $L : K$

Separation of EDX peaks



[\uparrow Wavelength-dispersive X-ray spectroscopy (WDXS)]

EPFL Periodic table of X-ray peaks

Energies in keV



| | | | | | | 2 |
|--|---|--|---|--|--|------------------------------|
| | | | | | | 4.003 He Helium |
| IIIA | IVA | VA | VIA | VIIA | | |
| 5 10.811 B Boron 0.185 | 6 12.011 C Carbon 0.277 | 7 14.007 N Nitrogen 0.392 | 8 15.999 O Oxygen 0.523 | 9 18.998 F Fluorine 0.677 | 10 20.180 Ne Neon 0.848 | |
| 13 26.982 Al Aluminum 1.486 0.073 | 14 28.086 Si Silicon 1.740 0.092 | 15 30.974 P Phosphorus 2.013 0.117 | 16 32.066 S Sulfur 2.307 0.149 | 17 35.453 Cl Chlorine 2.622 0.183 | 18 39.948 Ar Argon 2.957 0.221 | |
| 31 69.72 Ga Gallium 9.250 1.098 | 32 72.61 Ge Germanium 9.885 1.188 | 33 74.922 As Arsenic 10.542 1.282 | 34 78.96 Se Selenium 11.220 1.379 | 35 79.904 Br Bromine 11.922 1.480 | 36 83.80 Kr Krypton 12.649 1.586 0.093 | |
| 49 114.82 In Indium 24.209 3.286 0.370 | 50 118.71 Sn Tin 25.272 3.443 0.401 | 51 121.76 Sb Antimony 26.359 3.604 0.433 | 52 127.60 Te Tellurium 27.471 3.768 0.470 | 53 126.905 I Iodine 28.615 3.937 0.497 | 54 131.29 Xe Xenon 29.779 4.109 0.531 | |

No X-ray
because no 2s... e⁻
only 1s

← K peak

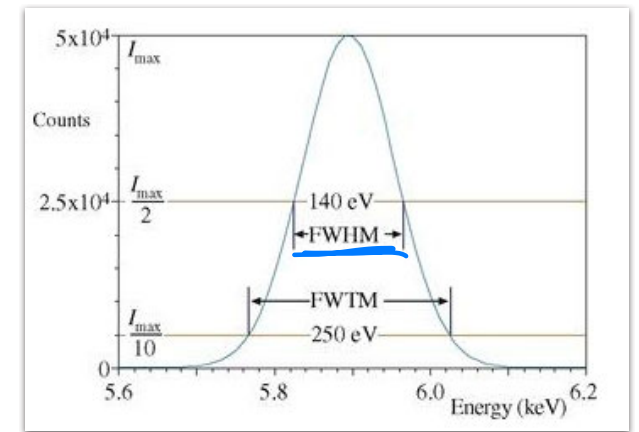
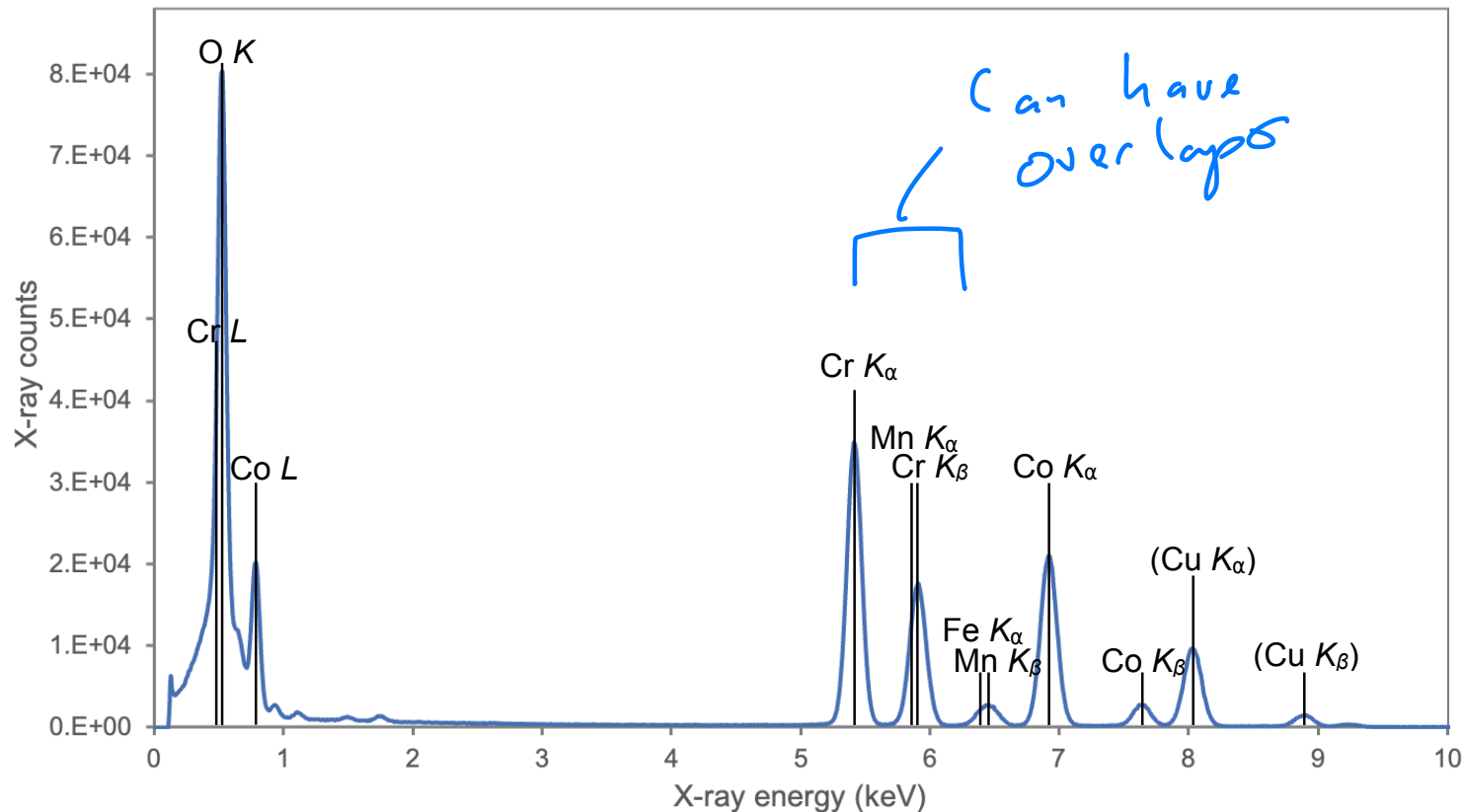
← K
← L

← K
← L
← M

As $z \uparrow$
X-ray energy \uparrow
because core-shell
e⁻ goes down
to deeper level

EPFL The EDX spectrum

- Example spectrum from fuel cell sample containing O, Cr, Mn, Fe, Co
- Spectrum of mostly well-defined peaks that e.g. can be fitted with Gaussians

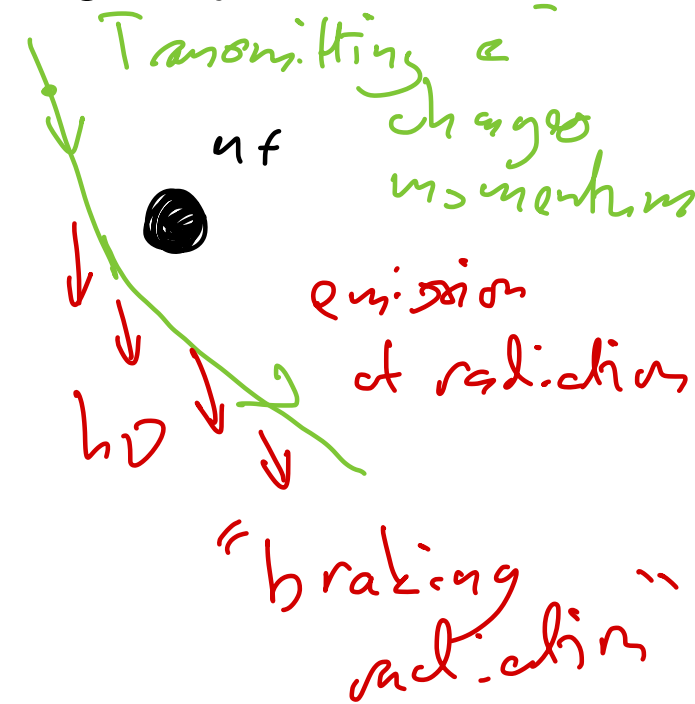
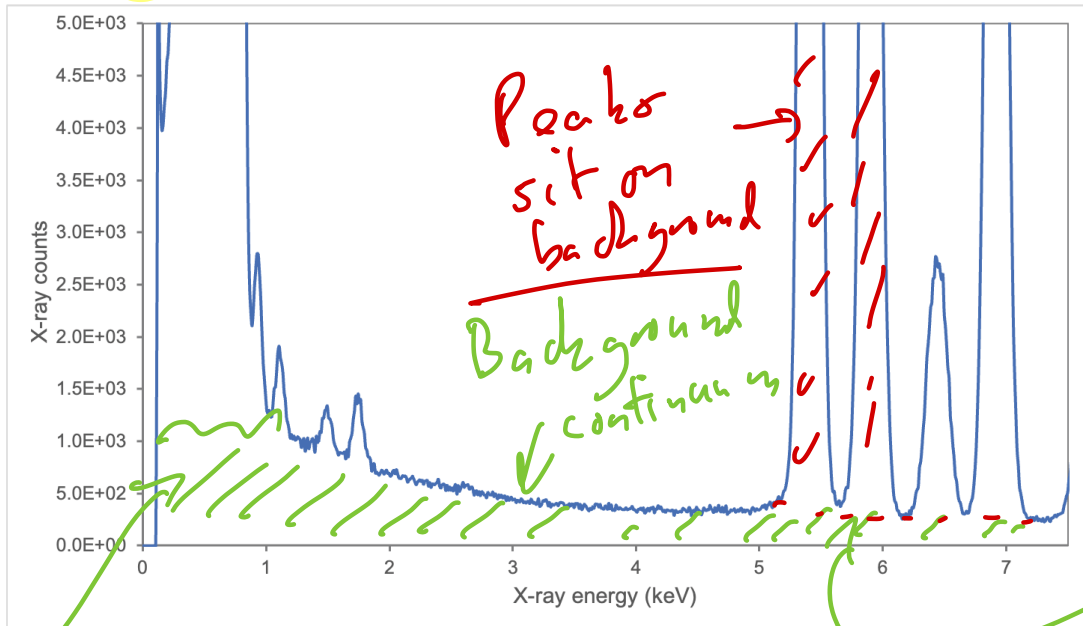


Width of peak determined by detector

typically 120 - 140 eV in width

EPFL Bremsstrahlung background

- Continuum background of radiation emitted when e^- velocity changed by atomic field
- Stronger at low keV; depends on atomic number Z



Fitting easy

"State-of-the-art" model by Chapman (down to 1 keV): $I_{\text{brem}} = \frac{\beta_0}{E_{\text{X-ray}}} + \beta_1 + \beta_2 E_{\text{X-ray}}$

Fitting challenge

$\beta_0, \beta_1, \beta_2$: empirical values

EPFL EDXS quantification

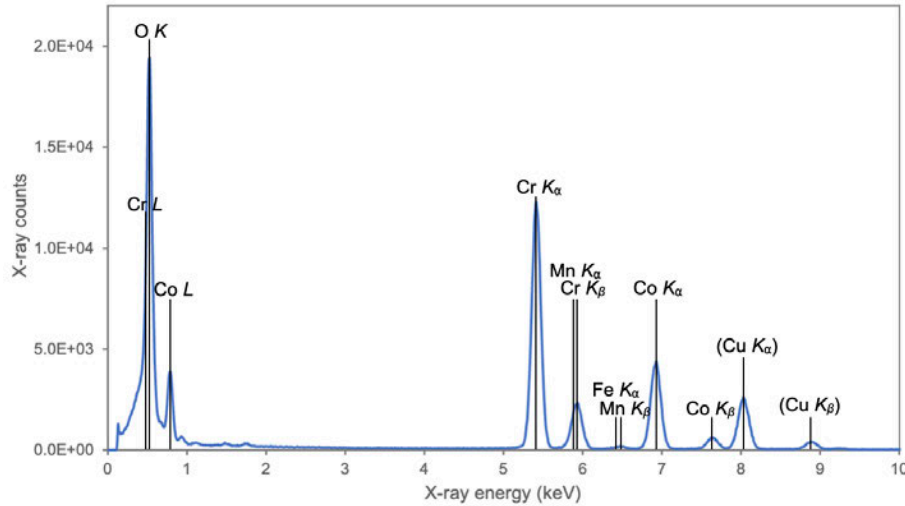
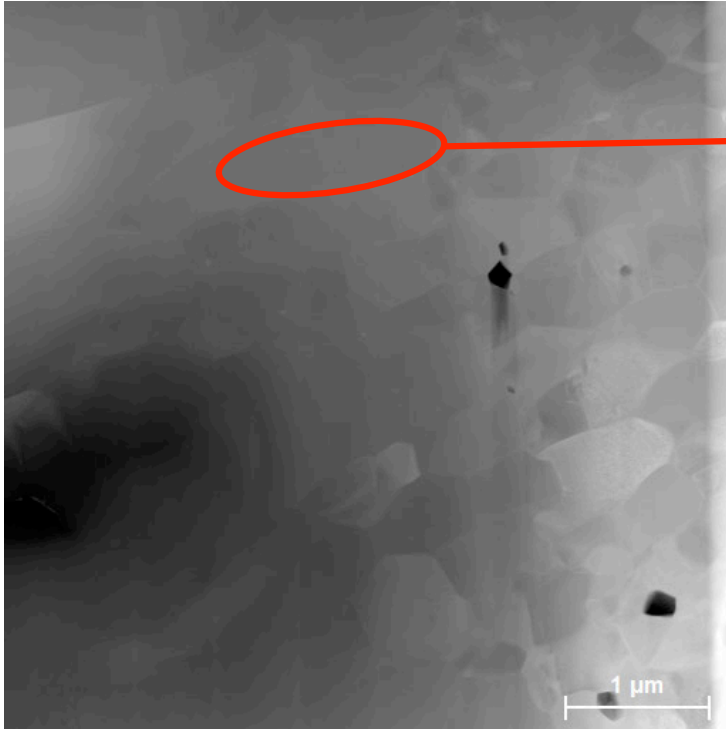
- To go from qualitative to quantitative: measure the intensities I_j of the X-ray peaks (area under the peak)
- Typically apply "Cliff-Lorimer" approach where calculate ratios of constituent elements:

$$\frac{C_A}{C_B} = k_{AB} \frac{I_A}{I_B}$$

- k_{AB} : k -factor
 - determined empirically by: standards / theoretical calculations / empirical models
- k -factors relate to probability of X-ray emission, probability of X-ray absorption and probability of unabsorbed X-ray being detected
- Rule of thumb: quantification accuracy 10–20%. However, much better (e.g. 1%) can be achieved in certain cases
- Detection limit: ~0.1 – a few at. %

EPFL EDXS quantification

- Example: Cr-rich grain in fuel cell spinel layer



| Element | Peak series | At. % |
|---------|-------------|-------|
| Cr | K | 33.7 |
| Co | K | 13.8 |
| Mn | K | 2.5 |
| Fe | K | 0.1 |
| O | K | 49.9 |

B_2 for relative accuracy
 ← 14% error

Spinel : AB_2O_4
 A, B, transition metals
 → 57 at% O

- 1-2 \rightarrow \leftarrow spread

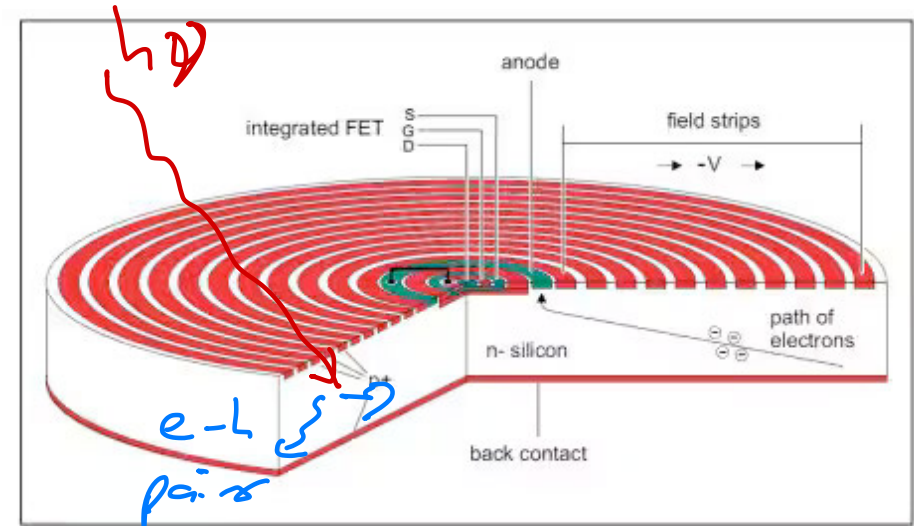
SEM: 30 keV beam, bulk sample



EPFL EDX detection

- Modern standard is the *Silicon Drift Detector (SDD)*
- Incident X-ray absorbed in Si creates e^-h^+ pairs
- Internal electric field drifts e^- charge towards anode
- Accumulated charge converted to voltage by a pre-amplifier
- Quantity of charge carriers depends on X-ray energy
⇒ measured voltage corresponds to energy of detected X-ray

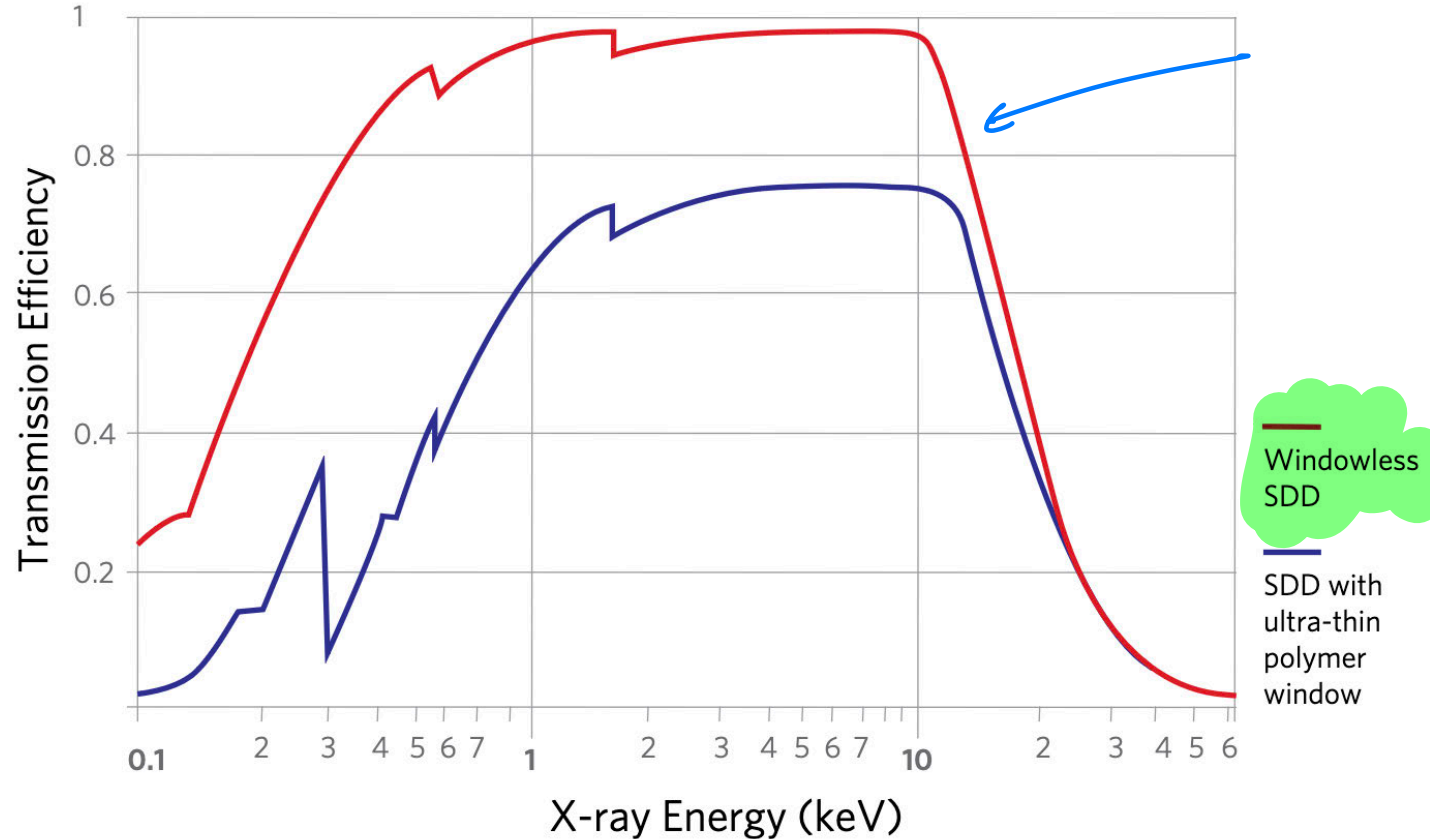
Detectors v. compact, v. fast



Example SDD detector design

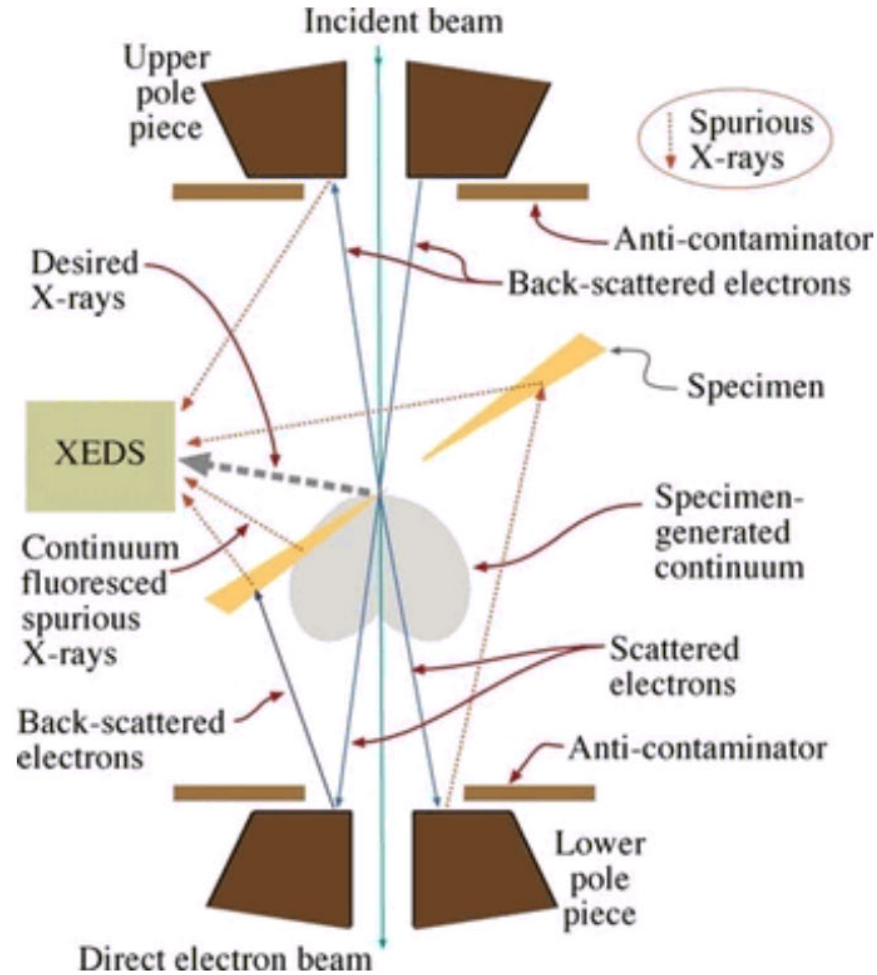


- SDD detectors are compact and fast, but poor DQE for X-rays ≥ 20 keV



Mostly use 0-20 keV range

EPFL Detection geometry



- Take care of spurious artefact X-ray peaks

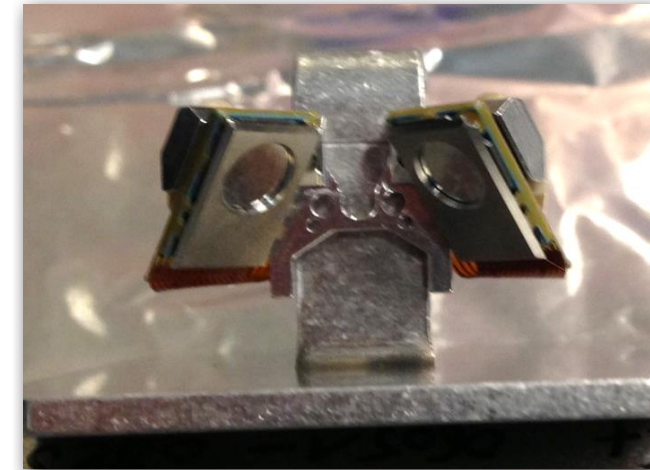
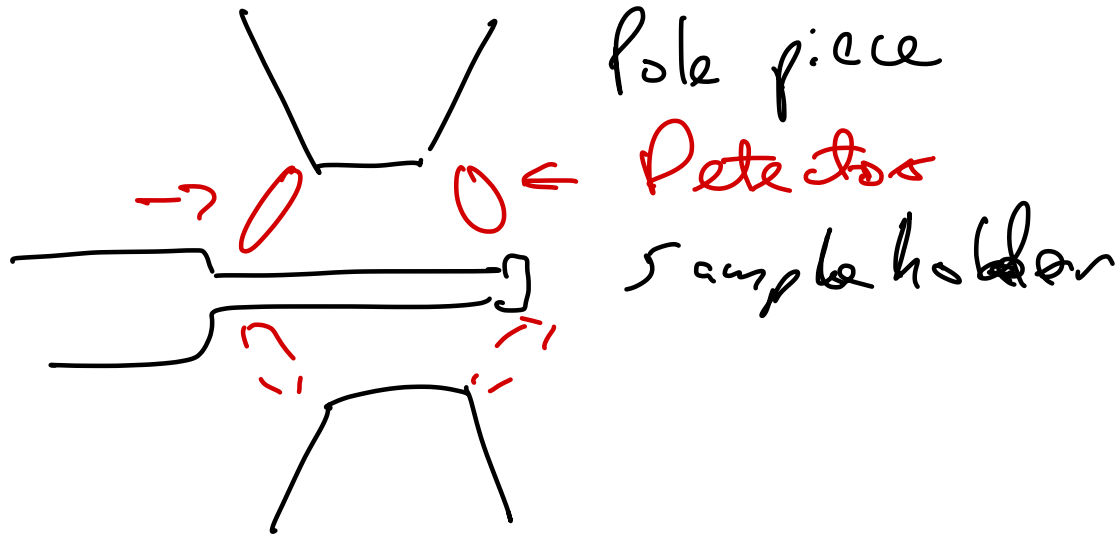
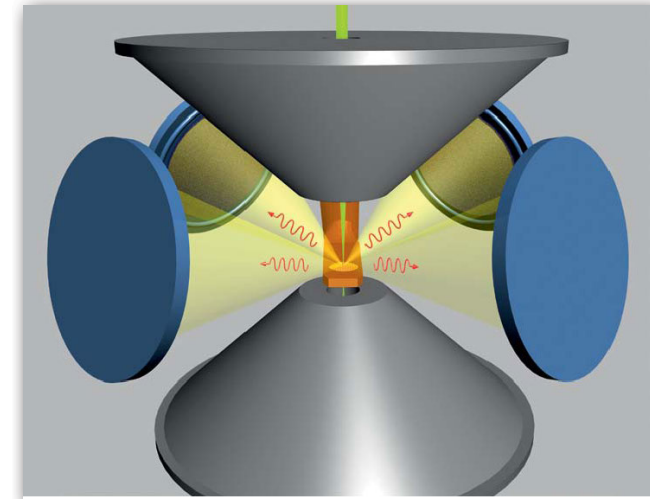
- Fluorescence of X-rays from support grid (e.g. Cu $K\alpha$, $K\beta$)

- Pole piece (Fe, Co, Cr) ?

EPFL Detection geometry

SDD: up to 50'000
counts/s

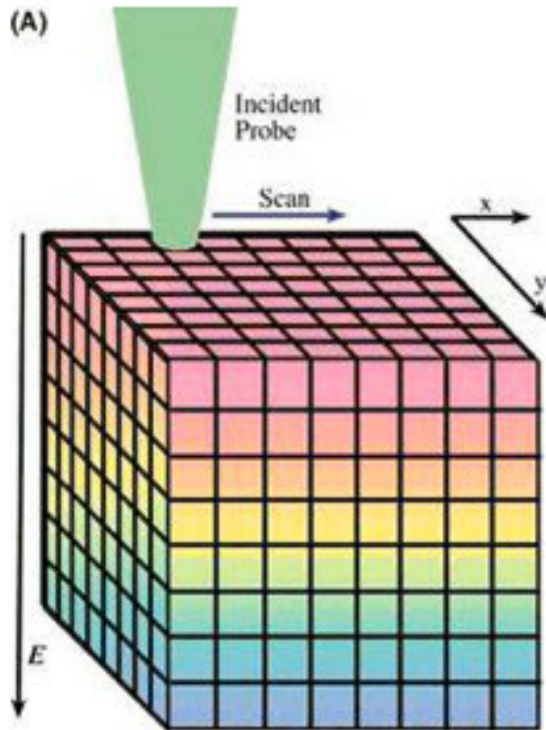
- New standard is to use multiple SDDs to increase solid angle of collection and hence detection efficiency
- For example: “Super-X” on Osiris, Titan with 4 quadrants giving ~ 1 Sr solid angle of collection
- State-of-the-art: Thermo Fisher Scientific Ultra with ~ 4 Sr



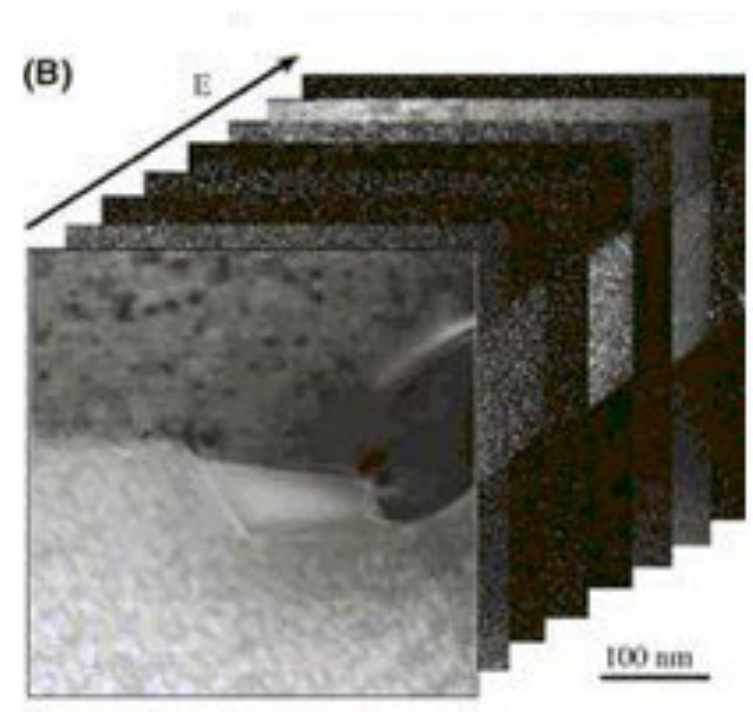
EPFL STEM-EDXS data-cube

- EDXS map: acquire one spectrum per pixel position (x, y)
- Gives 3D data-cube of information with axes (x, y, E)
- Data can be post-processed – integrate area under peak to generate qualitative elemental map

"Spectrum image"

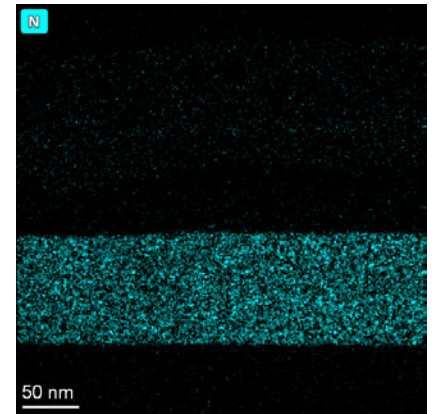
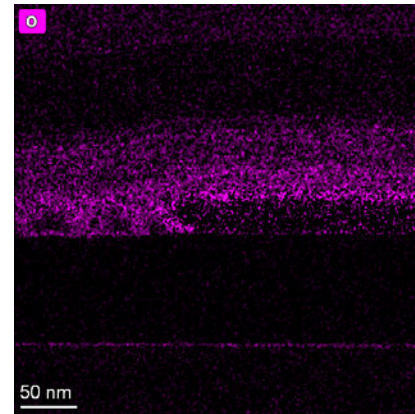
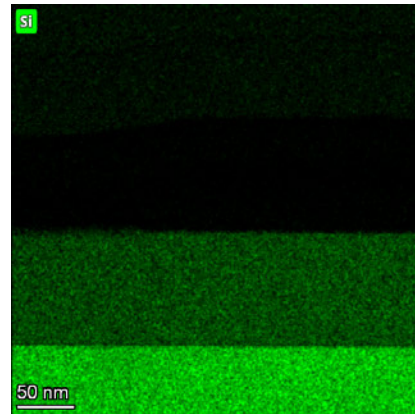
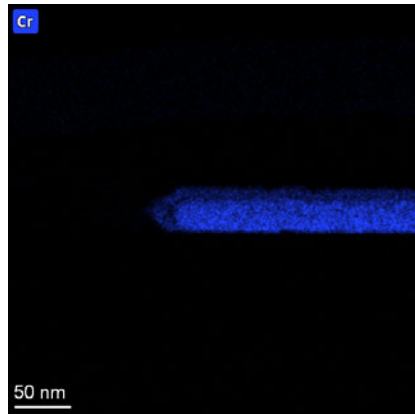
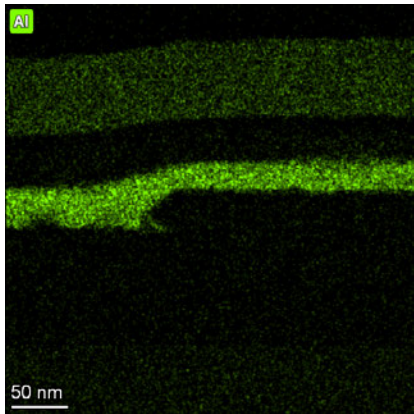
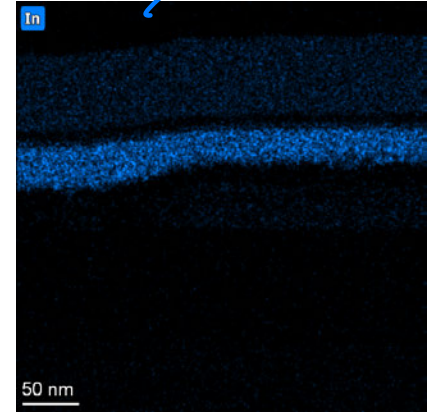
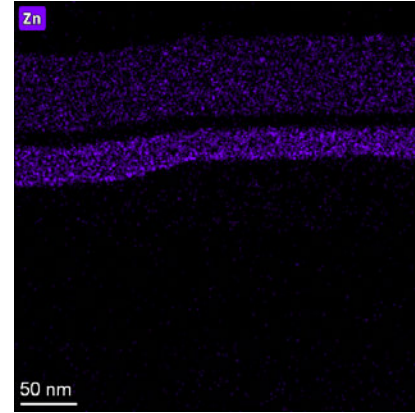
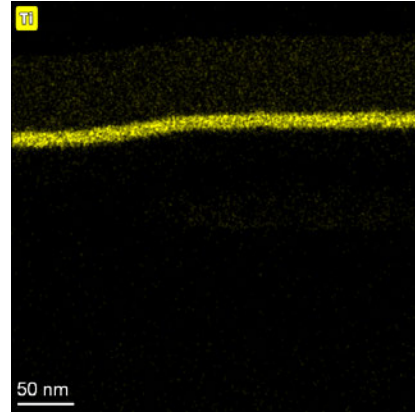
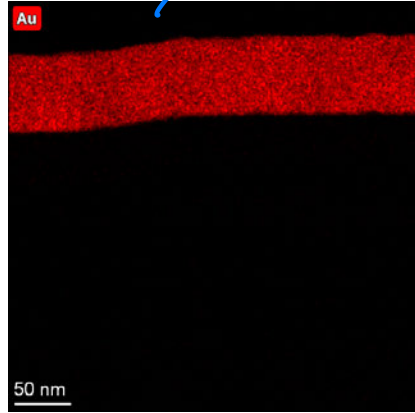
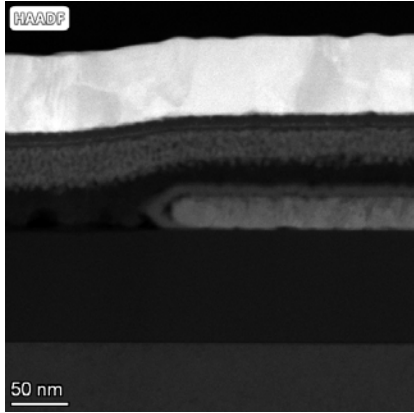


*Each position
(x, y)
Spectrum*



EPFL EDXS mapping: applications

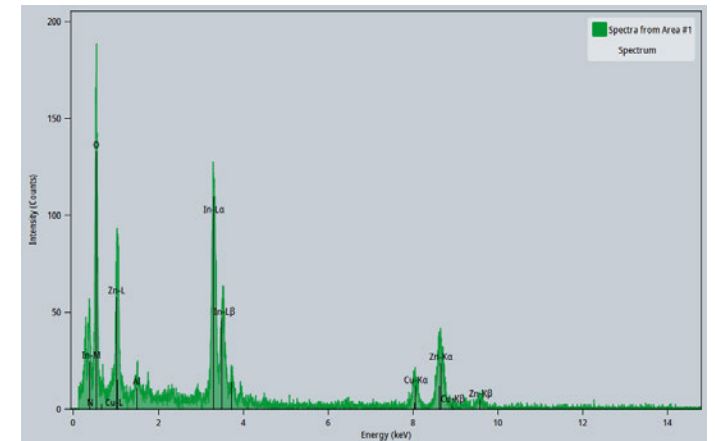
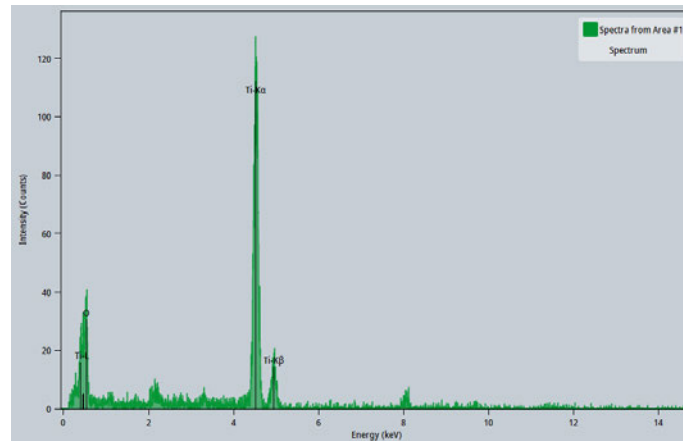
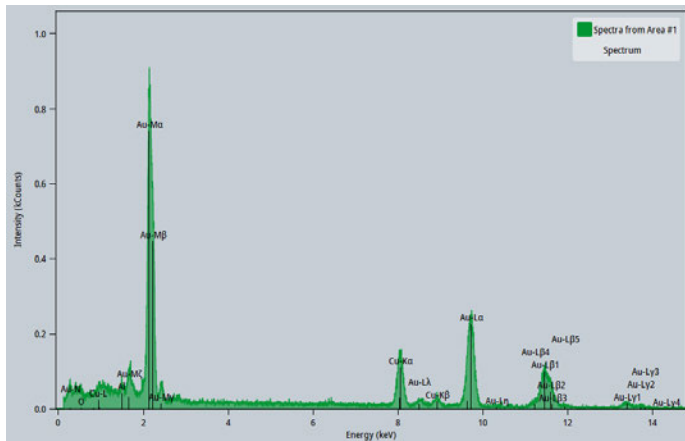
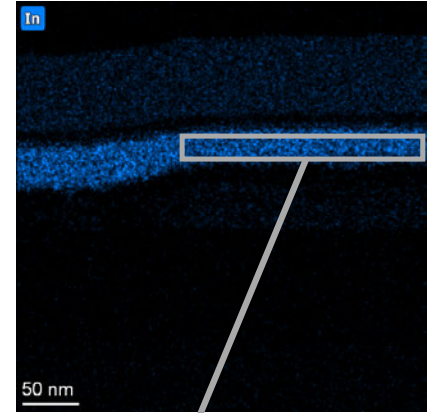
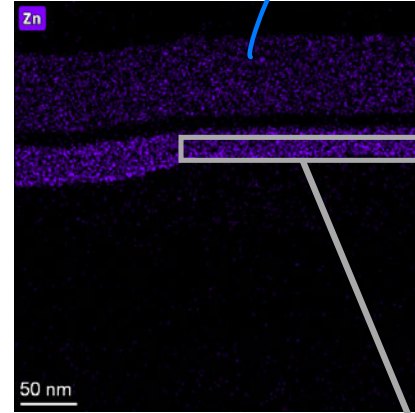
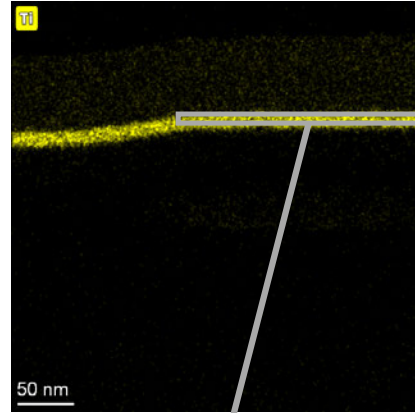
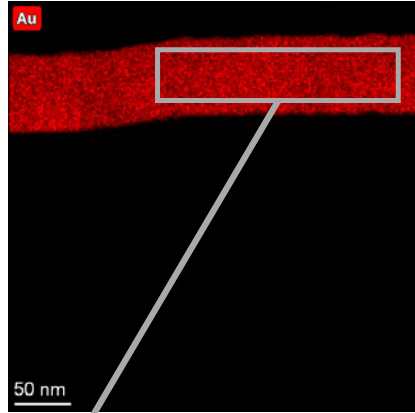
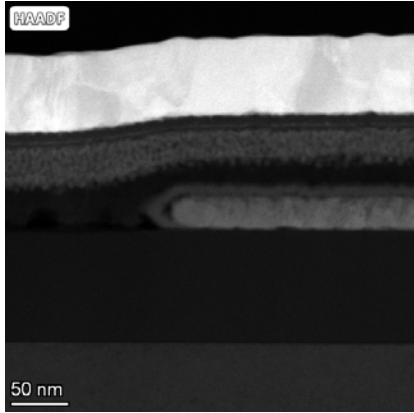
- Multilayer sample – *net counts* maps → Extra integrated signal
sum peaks
/ L peaks k-peaks



EPFL EDXS mapping: applications

- Multilayer sample – *integrated counts* EDX spectra

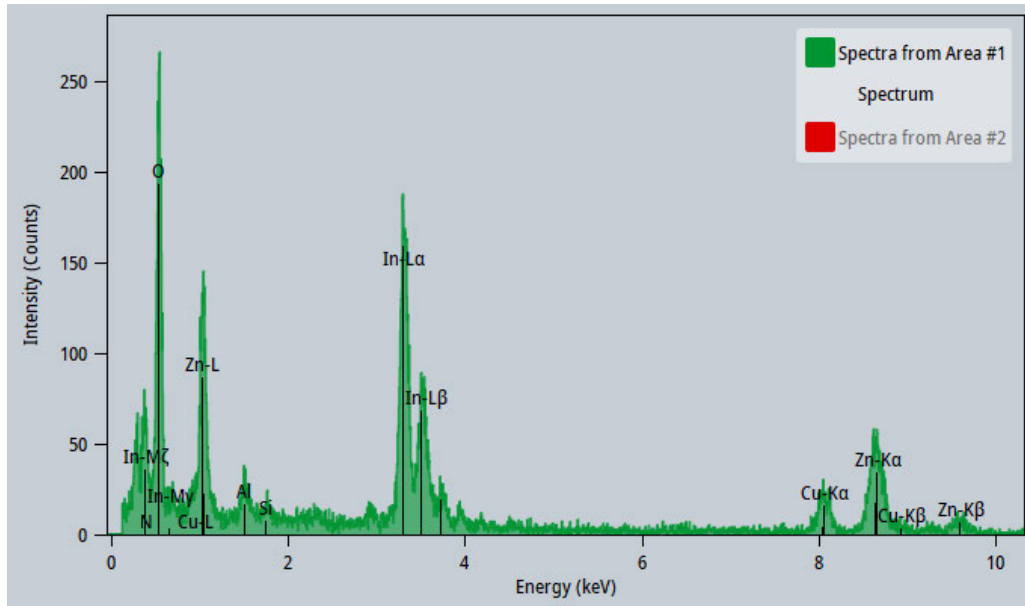
Fiducial signal
from
Bremsstrahlung
background



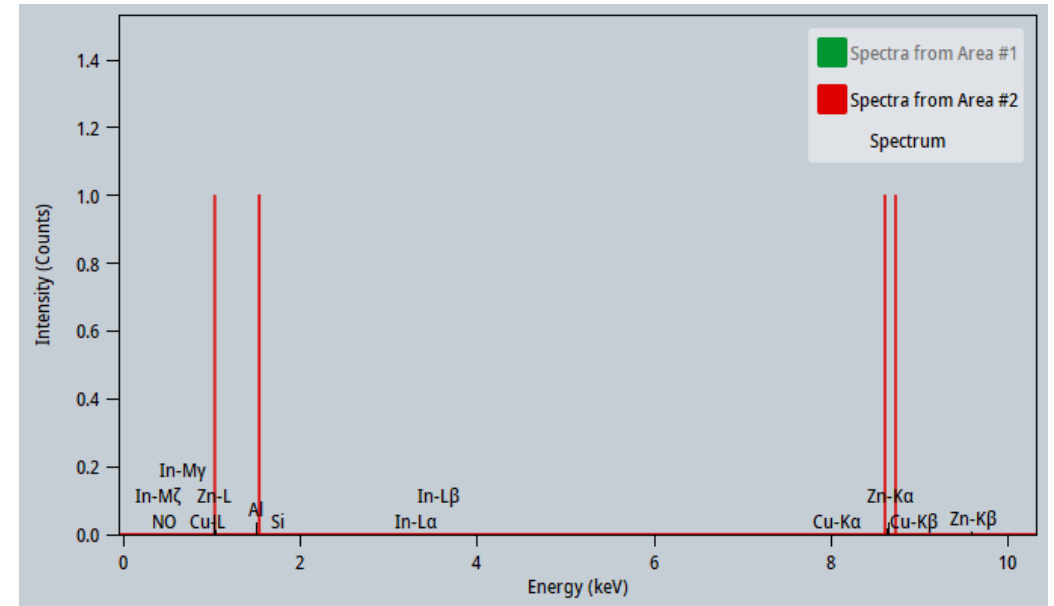
Why integrate counts across spatial ROI?

- In-Zn-O layer:

Integrated from $270 \times 25 = 6'750 \text{ px}^2$



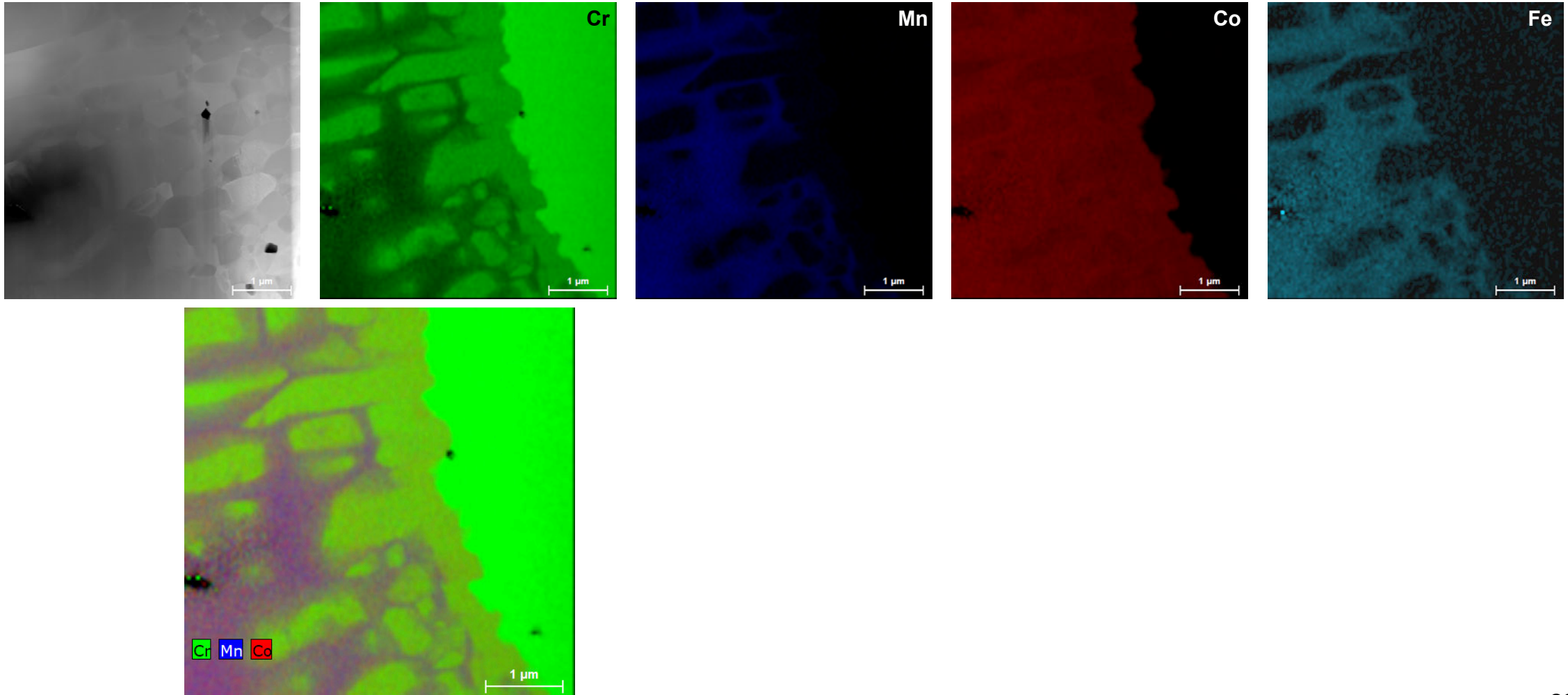
Single pixel spectrum



Poisson statistics : peak with counts N
 \Rightarrow Need $N = 10,000$ for 1% accuracy
 $\text{noise} = \sqrt{N}$

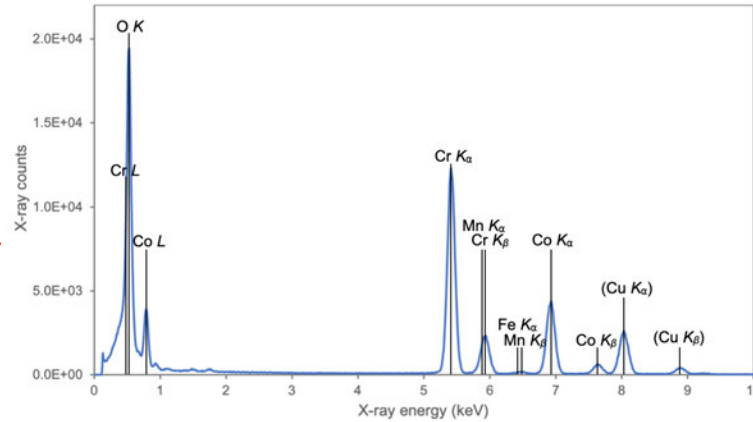
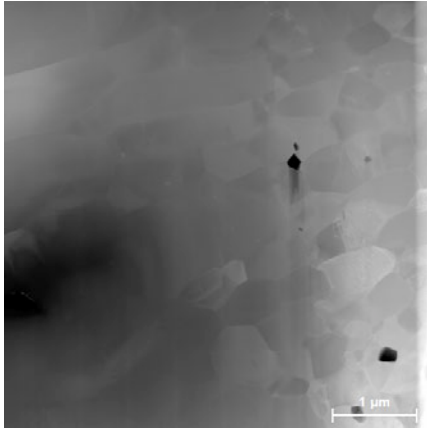
EPFL EDXS mapping: applications

- Fuel cell sample: Fe-doped MnCo_2O_4 spinel layer

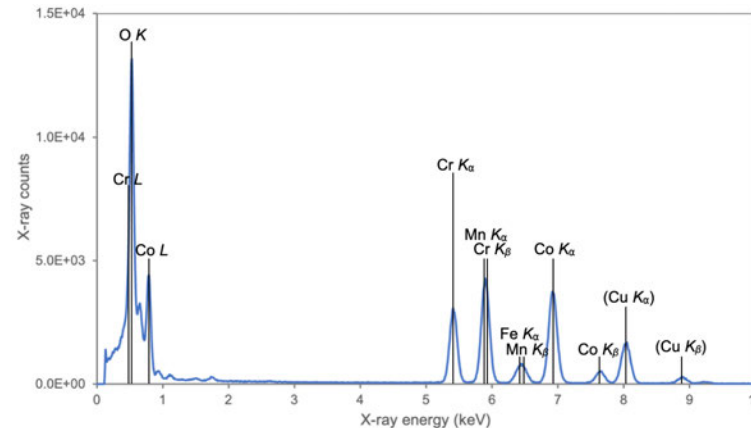
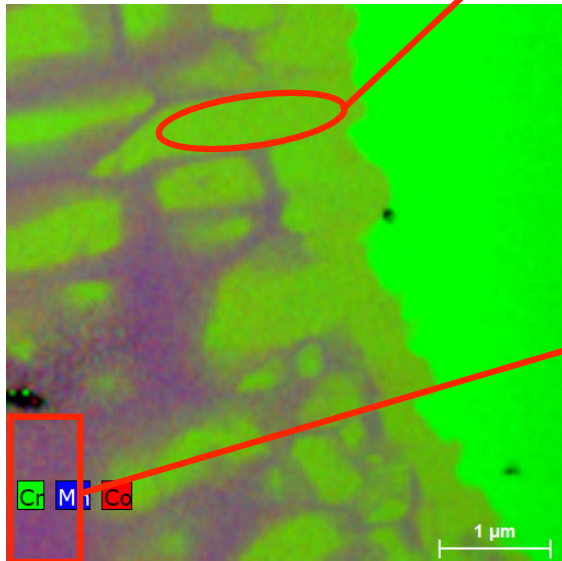


EPFL EDXS mapping: applications

- Fuel cell sample: Fe-doped MnCo_2O_4 spinel layer



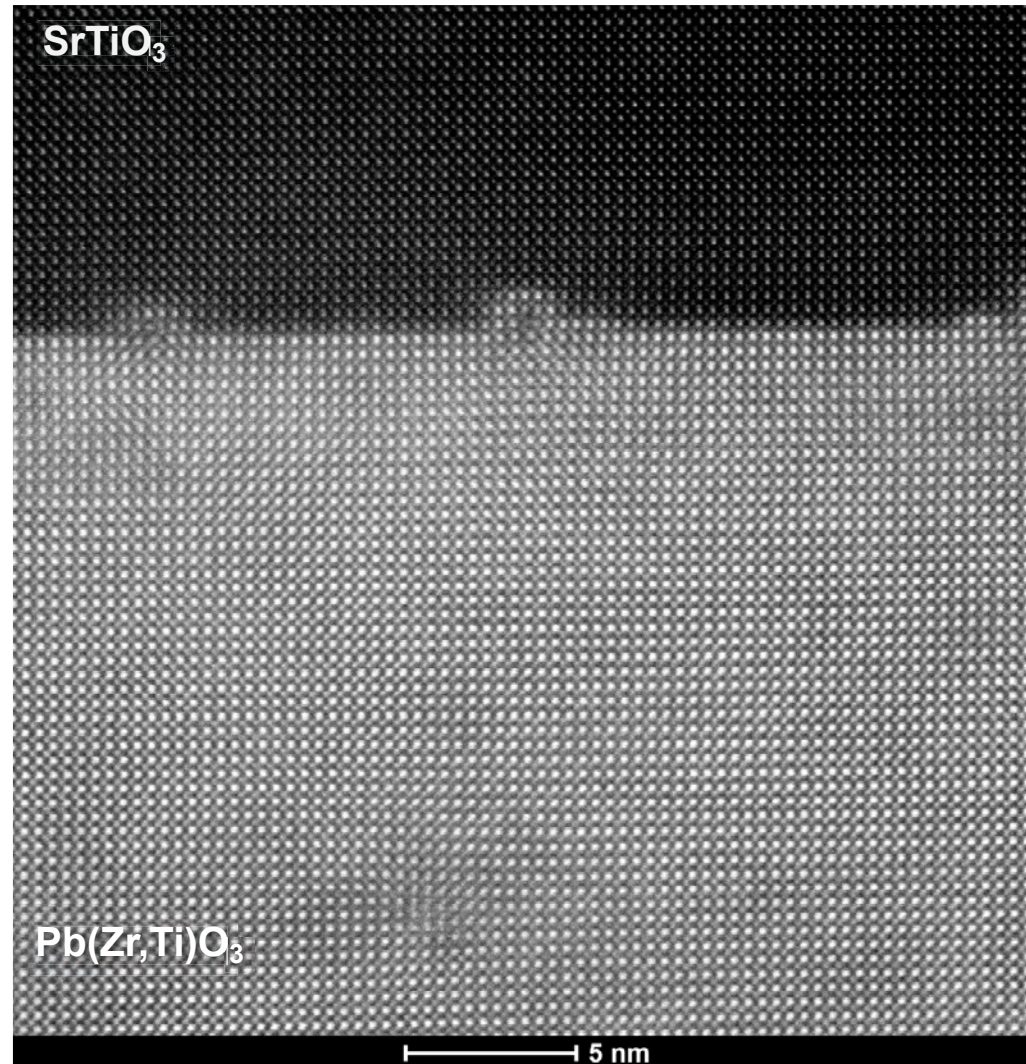
| Element | Peak series | At. % |
|---------|-------------|-------|
| Cr | K | 33.7 |
| Co | K | 13.8 |
| Mn | K | 2.5 |
| Fe | K | 0.1 |
| O | K | 49.9 |



| Element | Peak series | At. % |
|---------|-------------|-------|
| Cr | K | 12.5 |
| Co | K | 18.3 |
| Mn | K | 17.2 |
| Fe | K | 2.2 |
| O | K | 49.8 |

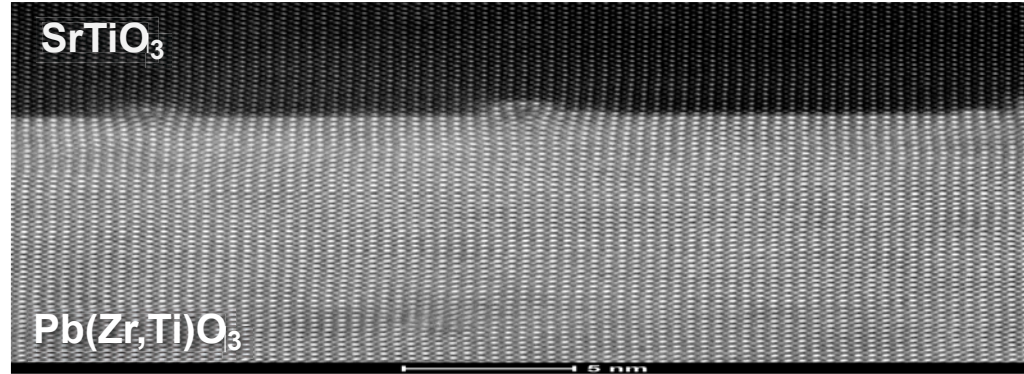
EPFL Atomic resolution EDXS with Cs-STEM

- Sample of $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$ on SrTiO_3

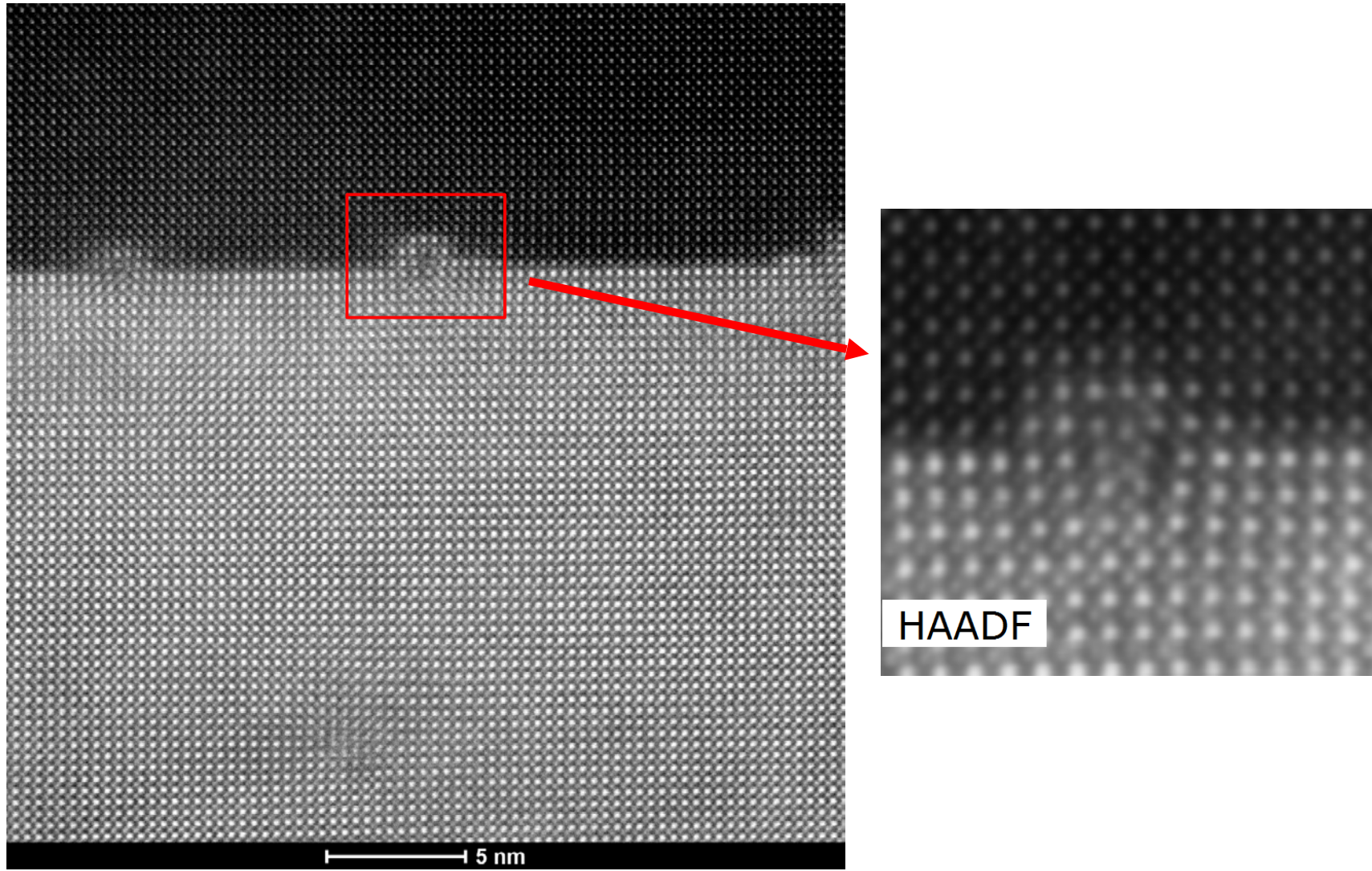


- Sample of $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$ on SrTiO_3

↙ Misfit dislocation



- Sample of $\text{Pb}(\text{Zr,Ti})\text{O}_3$ on SrTiO_3



EPFL Atomic resolution EDXS with Cs-STEM

- Sample of $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$ on SrTiO_3 – atomic resolution elemental mapping

